

Andrei A Gismatulin

List of Publications by Year in descending order

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papers

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citing authors

#	ARTICLE	IF	CITATIONS
1	Charge Transport and the Nature of Traps in Oxygen Deficient Tantalum Oxide. ACS Applied Materials & Interfaces, 2018, 10, 3769-3775.	8.0	45
2	Memristor effect in GeO[SiO ₂] and GeO[SiO] solid alloys films. Applied Physics Letters, 2019, 114, .	3.3	26
3	All Nonmetal Resistive Random Access Memory. Scientific Reports, 2019, 9, 6144.	3.3	24
4	Charge transport mechanism in the metalâ€“nitrideâ€“oxideâ€“silicon forming-free memristor structure. Applied Physics Letters, 2020, 116, .	3.3	24
5	Charge transport mechanism in SiN _x -based memristor. Applied Physics Letters, 2019, 115, 253502.	3.3	21
6	Charge transport mechanism in the forming-free memristor based on silicon nitride. Scientific Reports, 2021, 11, 2417.	3.3	21
7	Charge transport mechanism of high-resistive state in RRAM based on SiO _x . Applied Physics Letters, 2019, 114, .	3.3	18
8	Electronic structure and charge transport in nonstoichiometric tantalum oxide. Nanotechnology, 2018, 29, 264001.	2.6	16
9	Resistive Switching in Non-Stoichiometric Germanosilicate Glass Films Containing Ge Nanoclusters. Electronics (Switzerland), 2020, 9, 2103.	3.1	15
10	Optical properties and charge transport of textured Sc ₂ O ₃ thin films obtained by atomic layer deposition. Applied Surface Science, 2019, 478, 690-698.	6.1	14
11	Critical properties and charge transport in ethylene bridged organosilica low- $\hat{\epsilon}$ dielectrics. Journal of Applied Physics, 2020, 127, .	2.5	12
12	Electronic structure and charge transport mechanism in a forming-free SiO _x _x-based memristor. Nanotechnology, 2020, 31, 505704.	2.6	12
13	Charge transport mechanism in periodic mesoporous organosilica low-k dielectric. Applied Physics Letters, 2019, 115, 082904.	3.3	11
14	Charge transport mechanism in La:HfO ₂ . Applied Physics Letters, 2020, 117, .	3.3	11
15	Charge transport mechanism in the metalâ€“nitrideâ€“oxideâ€“silicon forming-free memristor structure. Chaos, Solitons and Fractals, 2021, 142, 110458.	5.1	6
16	Charge Transport Mechanism in a Formless Memristor Based on Silicon Nitride. Russian Microelectronics, 2020, 49, 372-377.	0.5	5
17	Bipolar conductivity in ferroelectric La:HfZrO films. Applied Physics Letters, 2021, 118, .	3.3	5
18	Charge Transport Mechanism in Atomic Layer Deposited Oxygenâ€“Deficient TaO _x Films. Physica Status Solidi (B): Basic Research, 2021, 258, 2000432.	1.5	4

#	ARTICLE	IF	CITATIONS
19	Nanowired structure, optical properties and conduction band offset of RF magnetron-deposited n-SiIn ₂ O ₃ :Er films.. Materials Research Express, 2020, 7, 125903.	1.6	4
20	Electrophysical properties of Si/SiO ₂ nanostructures fabricated by direct bonding. Technical Physics Letters, 2016, 42, 590-593.	0.7	3
21	Multiphonon trap ionization transport in nonstoichiometric SiN _x . Materials Research Express, 2019, 6, 036304.	1.6	3
22	Swift heavy ion stimulated formation of the Si quantum dots in Si/SiO ₂ multilayer heterostructures. , 2019, , .		3
23	Charge Transport Mechanism and Trap Origin in Methyl-terminated Organosilicate Glass Low- ϵ^* Dielectrics. Physica Status Solidi (A) Applications and Materials Science, 2021, 218, 2000654.	1.8	2
24	Memory Properties of SiO _x - and SiN _x -Based Memristors. Nanobiotechnology Reports, 2021, 16, 722-731.	0.6	2
25	Nanoscale Si/SiO ₂ multilayer structures produced by plasma-chemical technology. , 2009, , .		1
26	Laser pulse crystallization and optical properties of Si/SiO ₂ and Si/Si ₃ N ₄ multilayer nano-heterostructures. Proceedings of SPIE, 2013, , .	0.8	1
27	Formation of Si nanocrystals in SiO _x , SiO _x :C:H films and Si/SiO ₂ multilayer nano-heterostructures by pulse laser treatments. , 2014, , .		1
28	Mechanism of stress induced leakage current in Si ₃ N ₄ . Materials Research Express, 2019, 6, 076401.	1.6	1
29	Silicon Nanocrystals and Amorphous Nanoclusters in SiO _x and SiN _x : Atomic, Electronic Structure, and Memristor Effects. , 2020, , .		1
30	Charge Transport Mechanism in a PECVD Deposited Low-k SiOCH Dielectric. Journal of Electronic Materials, 2022, 51, 2521-2527.	2.2	1
31	The electrical properties of MOS-structures with silicon nanoballs incrustated in SiO ₂ layer. , 2009, , .		0
32	Nanoscale Si/SiO ₂ double-barrier structures produced by plasma-chemical technology. , 2010, , .		0